

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/629,882	DEVINE, JOHN C.	
Examiner		Art Unit		Page 1 of 1
Nguyen N. Hanh		2834		

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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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